

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/002,919	HYON, SEUNG-TAEK	
Examiner	Art Unit	
Khai M. Nouven	2617	

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Class	Subclass	Date	Examiner
see	previous		KN

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Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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